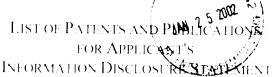
Serial No.: 09 955,517

Form PTO-1449 (Modified)



(Use several sheets if necessary)

Applicant: Tabery, et al.

Filing Date: 9 18 01

Atty Docket No.:

G0228

Group: 1746

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

1 vaminer Initial Document Number Date Name Class Francis Filing Date Office Of								IECEILE)
1C 1700	11	Docum	ent Number		Date	Name	Class	100 4 70/02
	13							C 170C

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Franslation
						Yes No
()						

OTHER ART(Including Author, Title, Date, Pertinent Pages, etc.)

N-	[-		Gerold David I. et al. Multiple Puch Fransmission and Phase Analysis of Six Types of Strong Phase-Shifting Masks. Pgs. 1-15				
,							
ρĹ	F		Neureuther, Andrew R. Exparability and Inspection Issues of Places and Phase Socrang Masks. http://buffy.eecs.berkelev.edu.IRO Summary 01abstracts kadam 1 html. Pgs. 1-3. Last viewed on July 20. 2001.				
		_					
pt "		_	Nau, X., et al., Specular Spectroscopic Scatterometry in DUV Lathography. Timbre Technology, Inc., et al.				
,							
EXAN			DATE CONSIDERED 4-2-63				

EXAMINER - Initial of reference considered, whether or not citation is in confirmance with MPE (now Than The through Station of not in conformance and not considere Include copy of this form with next communication to apply cart 8. HAM, AMD $\rho^{\rm TSA}(s)\rho^{\rm TSA}(s)$